


<b>Search Notes</b> 	<b>Application/Control No.</b> 10596625	<b>Applicant(s)/Patent Under Reexamination</b> SYFRIG, BENNO
	<b>Examiner</b> Bashaw, Heidi M	<b>Art Unit</b> 3709

SEARCHED			
Class	Subclass	Date	Examiner
433	152, 161, 165-166, 215	8.21.2007	HMB
606	80	8.21.2007	HMB
	Updated	3.28.2008	HMB

SEARCH NOTES		
Search Notes	Date	Examiner
W/ Wilson on above search	8.20.2007	HMB

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner